Se	Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	-
10/753,976	LIEW ET AL.	
Examiner	Art Unit	
John F. Ramirez	3737	

	SEAR	CHED	
Class	Subclass	Date	Examiner
378	54,56	3/3/2006	JFR
128	660.01	3/4/2006	JFR
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	·		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Plus search	3/2/2006	JFR
EAST Text search, backward/forward citations	3/3/2006	JFR
Inventor's name	3/3/2006	JFR
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